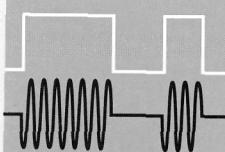


THIRD EDITION

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# MICROELECTRONIC CIRCUIT DESIGN

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10 20 30 40 50 60 70 80 90  
100 110 120 130 140 150 160  
170 180 190 200 210 220 230  
240 250 260 270 280 290 300  
310 320 330 340 350 360 370  
380 390 400 410 420 430 440  
450 460 470 480 490 500 510  
520 530 540 550 560 570 580  
590 600 610 620 630 640 650  
660 670 680 690 700 710 720  
730 740 750 760 770 780 790  
800 810 820 830 840 850 860  
870 880 890 900 910 920 930  
940 950 960 970 980 990 1000



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